

Title (en)

METHOD OF WIRE BONDING, SEMICONDUCTOR DEVICE, CIRCUIT BOARD, ELECTRONIC DEVICE AND WIRE BONDER

Title (de)

DRAHTBAND-METHODE, HALBLEITER, LEITERPLATTE, ELEKTRONIKELEMENT UND DRAHTBANDER

Title (fr)

TECHNIQUE DE SOUDAGE DE FILS, DISPOSITIF SEMI-CONDUCTEUR, CARTE DE CIRCUIT IMPRIME, DISPOSITIF ELECTRONIQUE ET POSTE DE SOUDURE

Publication

**EP 1069608 A4 20040811 (EN)**

Application

**EP 00900809 A 20000119**

Priority

- JP 0000214 W 20000119
- JP 1382599 A 19990122

Abstract (en)

[origin: EP1069608A1] A wire bonding method comprising: disposing a plurality of leads (20) aligned in an imaginary plane (P) around the periphery of a semiconductor chip (10) having a plurality of electrodes (12) aligned on an imaginary straight line (L1); bonding wires (30) to the electrodes (12); bending the wires (30) toward the leads (20) as viewed from a direction perpendicular to the imaginary plane (P); and bonding the wires (30) to the leads (20). <IMAGE>

IPC 1-7

**H01L 21/60; H01L 21/00; H01L 23/495**

IPC 8 full level

**H01L 21/60** (2006.01); **H01L 21/607** (2006.01); **H01L 23/495** (2006.01)

CPC (source: EP KR US)

**H01L 21/60** (2021.08 - KR); **H01L 23/4952** (2013.01 - EP US); **H01L 24/48** (2013.01 - EP US); **H01L 24/49** (2013.01 - EP US);  
**H01L 24/85** (2013.01 - EP US); **H01L 24/78** (2013.01 - EP US); **H01L 2224/05553** (2013.01 - EP US); **H01L 2224/05599** (2013.01 - EP US);  
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**H01L 2924/12041** (2013.01 - EP US); **H01L 2924/14** (2013.01 - EP US); **H01L 2924/15311** (2013.01 - EP US); **H01L 2924/181** (2013.01 - EP US);  
**H01L 2924/19041** (2013.01 - EP US); **H01L 2924/19043** (2013.01 - EP US)

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Designated contracting state (EPC)

DE FR GB

DOCDB simple family (publication)

**EP 1069608 A1 20010117; EP 1069608 A4 20040811; EP 1069608 B1 20070314**; DE 60033888 D1 20070426; JP 2000216188 A 20000804;  
KR 100388728 B1 20030625; KR 20010092255 A 20011024; TW 480633 B 20020321; US 6437453 B1 20020820; WO 0044040 A1 20000727

DOCDB simple family (application)

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TW 89101026 A 20000121; US 64664100 A 20001026